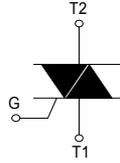
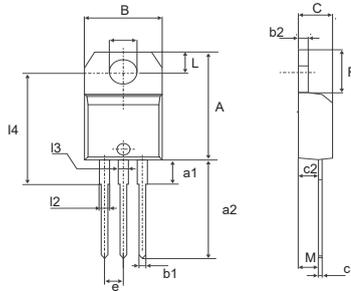


BTA06

Discrete Triacs(Isolated)



Dimensions TO-220AB



REF.	Millimeters			Inches		
	Min.	Typ.	Max.	Min.	Typ.	Max.
A	15.20		15.90	0.598		0.625
a1		3.75			0.147	
a2	13.00		14.00	0.511		0.551
B	10.00		10.40	0.393		0.409
b1	0.61		0.88	0.024		0.034
b2	1.23		1.32	0.048		0.051
C	4.40		4.60	0.173		0.181
c1	0.49		0.70	0.019		0.027
c2	2.40		2.72	0.094		0.107
e	2.40		2.70	0.094		0.106
F	6.20		6.60	0.244		0.259
ØI	3.75		3.85	0.147		0.151
I4	15.80	16.40	16.80	0.622	0.646	0.661
L	2.65		2.95	0.104		0.116
I2	1.14		1.70	0.044		0.066
I3	1.14		1.70	0.044		0.066
M		2.60			0.102	

	V _{DRM/RRM}	V _{DSM/RSM}
	V	V
BTA06-200	200	300
BTA06-400	400	500
BTA06-600	600	700
BTA06-800	800	900
BTA06-1000	1000	1100
BTA06-1200	1200	1300



ABSOLUTE MAXIMUM RATINGS

Symbol	Parameter	Value	Unit
$I_{T(RMS)}$	RMS on-state current (full sine wave)	TO-220AB $T_c = 100^\circ\text{C}$	6 A
I_{TSM}	Non repetitive surge peak on-state current (full cycle, T_j initial = 25°C)	F = 60 Hz t = 16.7 ms	63 A
		F = 50 Hz t = 20 ms	60 A
I^2t	I^2t value for fusing	tp = 10 ms	21 A ² s
dI/dt	Critical rate of rise of on-state current $I_G = 2 \times I_{GT}$, tr ≤ 100 ns	F = 120 Hz $T_j = 125^\circ\text{C}$	50 A/μs
I_{GM}	Peak gate current	tp = 20 μs $T_j = 125^\circ\text{C}$	4 A
V_{ISO}	Isolation Voltage, 1min		2500 VAC
T_{stg} T_j	Storage junction temperature range Operating junction temperature range		- 40 to + 150 - 40 to + 125 °C

ELECTRICAL CHARACTERISTICS ($T_j = 25^\circ\text{C}$, unless otherwise specified)

■ SNUBBERLESS and LOGIC LEVEL(3 Quadrants)

Symbol	Test Conditions	Quadrant	BTA06		Unit	
			CW	BW		
$I_{GT(1)}$	$V_D = 12\text{V}$ R=30Ω	I - II - III	MAX.	35	50	mA
V_{GT}		I - II - III	MAX.	1.3		V
V_{GD}	$V_D = V_{DRM}$ $R_L = 3.3\text{k}\Omega$ $T_j = 125^\circ\text{C}$	I - II - III	MIN.	0.2		V
$I_H(2)$	$I_T = 100\text{mA}$		MAX.	35	50	mA
I_L	$I_G = 1.2 I_{GT}$	I - III	MAX.	50	70	mA
		II		60	80	
dV/dt(2)	$V_D = 67\% V_{DRM}$ gate open $T_j = 125^\circ\text{C}$		MIN.	400	1000	V/μs
(dI/dt)c(2)	Without snubber $T_j = 125^\circ\text{C}$		MIN.	3.5	5.3	A/ms



BTA06

Discrete Triacs(Isolated)

■ STANDARD (4Quadrants)

Symbol	Test Conditions	Quadrant		Value	Unit
$I_{GT(1)}$	$V_D=12V R_L=30\Omega$	I - II - III IV	MAX.	50 100	mA
V_{GT}		ALL	MAX.	1.3	V
V_{GD}	$V_D=V_{DRM} R_L=3.3\Omega T_j=125^\circ C$	ALL	MIN.	0.2	V
$I_H(2)$	$I_T=500mA$		MAX.	50	mA
I_L	$I_G=1.2I_{GT}$	I - III - IV	MAX.	50	mA
		II		100	
$dV/dt(2)$	$V_D=67\% V_{DRM}$ gate open $T_j=125^\circ C$		MIN.	400	V/ μs
$(dV/dt)_c(2)$	$(dI/dt)_c=2.7 A/ms T_j=125^\circ C$		MIN.	10	V/ μs

STATIC CHARACTERISTICS

Symbol	Test Conditions		Value	Unit
$V_{TM(2)}$	$I_{TM}=5.5A t_p=380\mu s$	$T_j=25^\circ C$	MAX.	1.55 V
$V_{to(2)}$	Threshold voltage	$T_j=125^\circ C$	MAX.	0.85 V
$R_{d(2)}$	Dynamic resistance	$T_j=125^\circ C$	MAX.	60 m Ω
I_{DRM} I_{RRM}	$V_{DRM}=V_{RRM}$	$T_j=25^\circ C$	MAX.	5 μA
		$T_j=125^\circ C$		1 mA

Note 1: minimum IGT is guaranteed at 5% of IGT max.

Note 2: for both polarities of A2 referenced to A1

THERMAL RESISTANCES

Symbol	Parameter	Value	Unit
$R_{th(j-c)}$	Junction to case (AC)	1.8	$^\circ C/W$
$R_{th(j-a)}$	Junction to ambient	60	$^\circ C/W$

PRODUCT SELECTOR

Part Number	Voltage (xxx)		Sensitivity	Type	Package
	200 V	~ 1200 V			
BTA06	X	X	50 mA	Standard	TO-220AB

OTHER INFORMATION

Part Number	Marking	Weight	Base quantity	Packing mode
BTA06	BTA06	2 g	250	Bulk



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Discrete Triacs(Isolated)

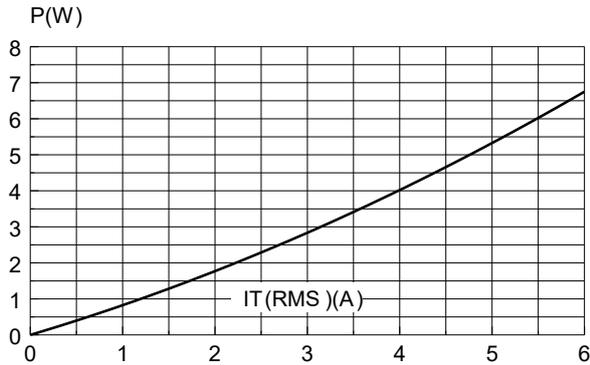


Fig.1:Maximum power dissipation versus RMS on-state current (full cycle).

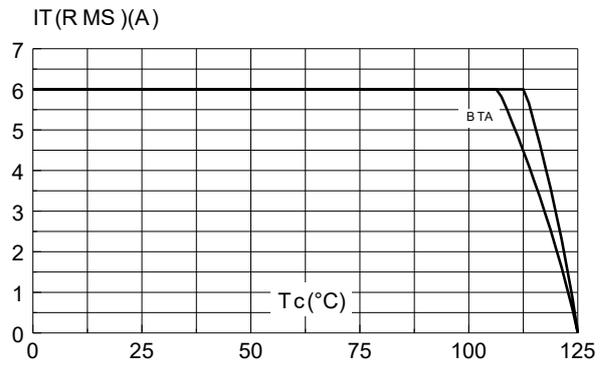


Fig.2:RMS on-state current versus case temperature(full cycle).

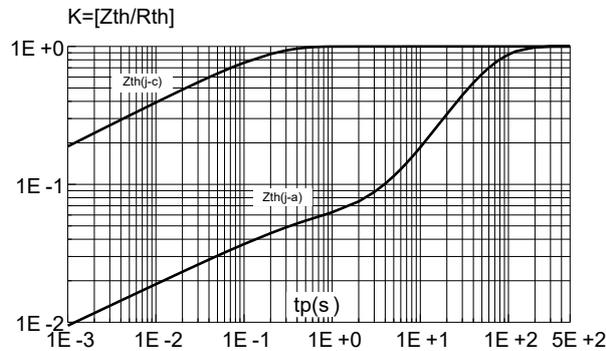


Fig.3:Relative variation of thermal impedance versus pulse duration.

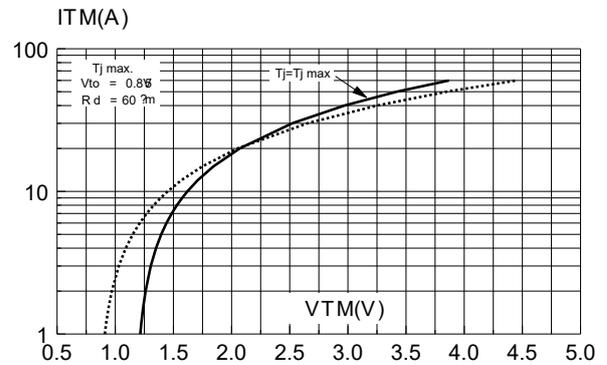


Fig.4:On-state characteristics(maximum values).

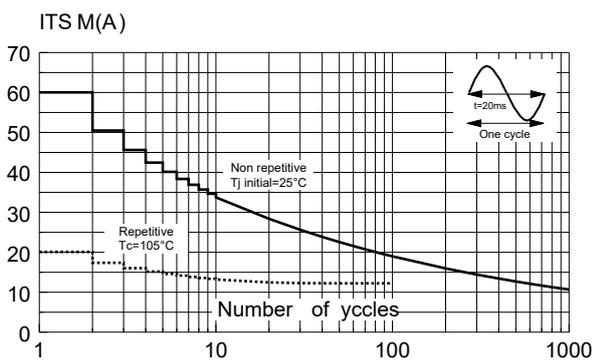


Fig.5:Surge peak on-state current versus number of cycles .

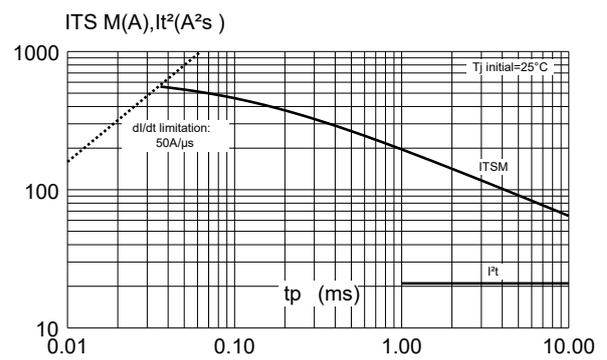


Fig.6:Non-repetitive surge peak on-state current for a sinusoidal pulse with width $tp < 10ms$, and corresponding value of I^2t .

BTA06

Discrete Triacs(Isolated)

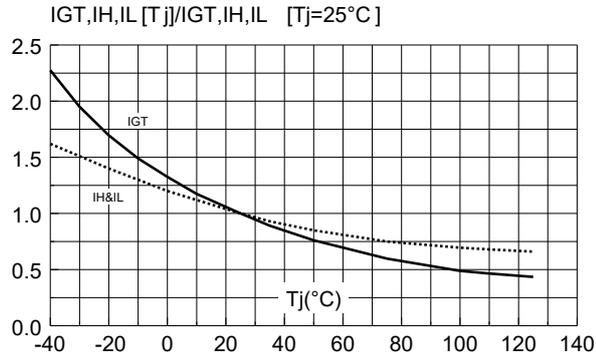


Fig.7:Relative variation of gate trigger current, holding current and latching current versus junction temperature (typical values).

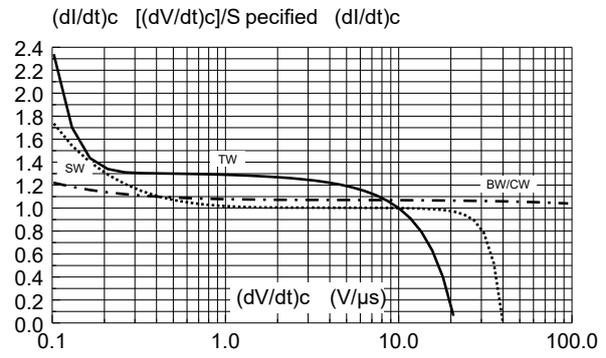


Fig.8-1:Relative variation of critical rate of decrease of main current versus (dV/dt)_c (typical values).S nubberles s&Logic Level Types

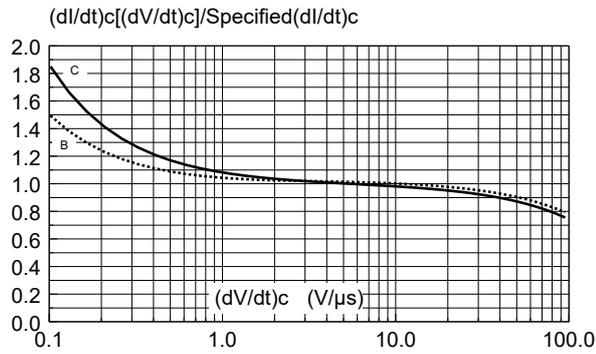


Fig.8-2:Relative variation of critical rate of decrease of main current versus (dV/dt)_c (typical values). Standard Types

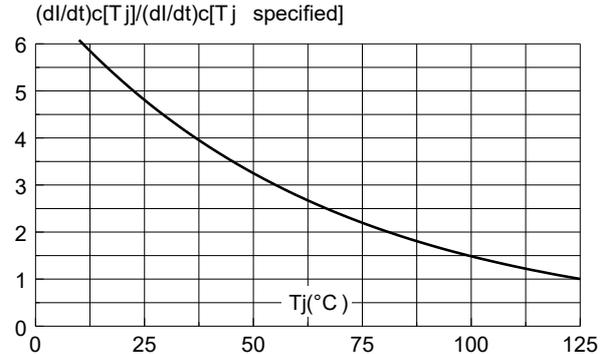


Fig.9:Relative variation of critical rate of decrease of main current vers us junction temperature.